



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 17.0004-01

CB Certificate No.: DEKRA-C11B-001

Schedule Number: IECQ-L DEKRA 17.0004-01-S Rev No.: 1 Rev. Date: 2017/12/21 Page 1 of 1

1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA includes FIB (Focused Ion Beam), SEM (Scanning electron microscope)	MIL-STD-883 Method 2018.4 JESD22A121 JESD201	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes Electrical Analysis and Physical Analysis with Sample Preparation (Decap, X-section, etc)	MIL-STD-883 Method 2009.9 IPC-A-610; IPC-A-600 MIL-STD-883 Method 2008.4 JESD22A121; JESD201 IPC-TM-650 2.1.1; IPC-6012	Or customer specified test
Failure and material analysis of semiconductor IC, electronic components and PCB/PCBA, includes NDE (Non-destructive Testing)	MIL-STD-883 Method 2012.7 J-STD-035; J-STD-020	Or customer specified test
2nd level integration platform service. (Includes Pre-SMT/SMT / Temperature Cycling test /Thermal Shock test/ Drop test/ Shock test / Vibration test/ Bending test / gross leak test /dye & pry test /solderability test /Wire Bond Shear&Wire Bond Pull test / Physical Dimensions measurement /Solder Ball Shear test /Die Shear test)	Industrial (JESD 47) ,JESD-22-A104/IPC-9701/MIL-STD-883 /JESD22-A106/JESD22-B104/JESD22-B110/JESD22-B111/JESD22-B103/JEITA ED-4702/IPC-JEDEC-9702/IEC 60068-2-21-2006/SEMI G86-0303/AEC-Q200-003/005/IPC-610F/IPC-7525/JEDEC JESD22-B102/JEDEC JESD22-B100	Or customer specified test
Accelerated environment reliability stress tests (Includes Pre-condition / MSL / Accelerated Temperature-Humidity test / Temperature-Humidity with bias test / Temperature Cycling test / Power and temperature cycling test / Low Temperature storage test /high temperature storage test /Highly Accelerated Stress Test/Autoclave Test//Thermal Shock Test)	JESD 47, J-STD-020, JESD22-series; IEC-60068-series, MIL-STD-202/750/810/883, JESDJP001; EIA-364-32C, EIAJED-4701, AEC-Q100; AEC-Q101, AEC-Q200,	Or customer specified test
Accelerated lifetime simulation tests. (Includes Operating Life test / Early life failure rate test/ Endurance and Data retention test / Electro-Migration /Miscellaneous test)	JESD 47, JESD22-A108/A117, JESD61, MIL-STD-202/750/810/883, AEC-Q100; AEC-Q101, AEC-Q200,	Or customer specified test
Electrostatic discharge test. (Including : HBM / MM / CDM / Latch Up / ESD Gun)	JESD 47 , JEDEC22-A114/A115/C101, EIA/JESD78, ANSI JEDEC ESDA JS001/JS002; AEC-Q100-002/003/004/011, AEC-Q101-001/002/005, AEC-Q200-002, JEITA ED4701; IEC61000-4-2, MIL-STD-883	Or customer specified test

This schedule is only valid in conjunction with the referenced Certificate of Approval

This approval and any schedule(s) may only be reproduced in full.

This approval is not transferable and remains the property of the issuing body.

The Status and authenticity of this approval and any schedule(s) may be verified by visiting the Official IECQ Website. www.iecq.org



DEKRA Certification B.V. Meander 1051, Arnhem. Netherlands